

Electronic Supplementary Information

Synthesis and Characterization 1D Co/CoFe₂O₄ Composites with Tunable Morphologies

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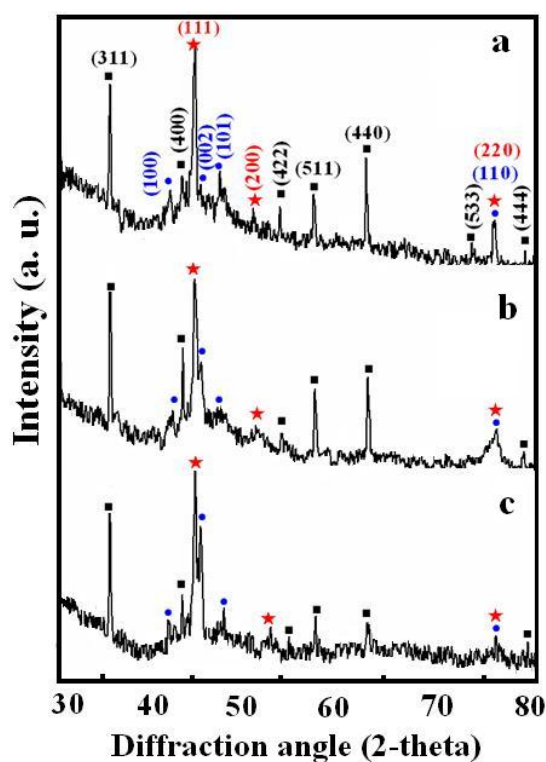


Figure S1 XRD patterns of Co/CoFe₂O₄ composites obtained with different NaOH quantities: (a) 2 g, (b) 3 g, and (c) 4 g. Black squares represent CoFe₂O₄ ferrite; blue spheres indicate Co metal with hexagonal packed structure; red pentagrams show Co metal with face-centered cubic structure.

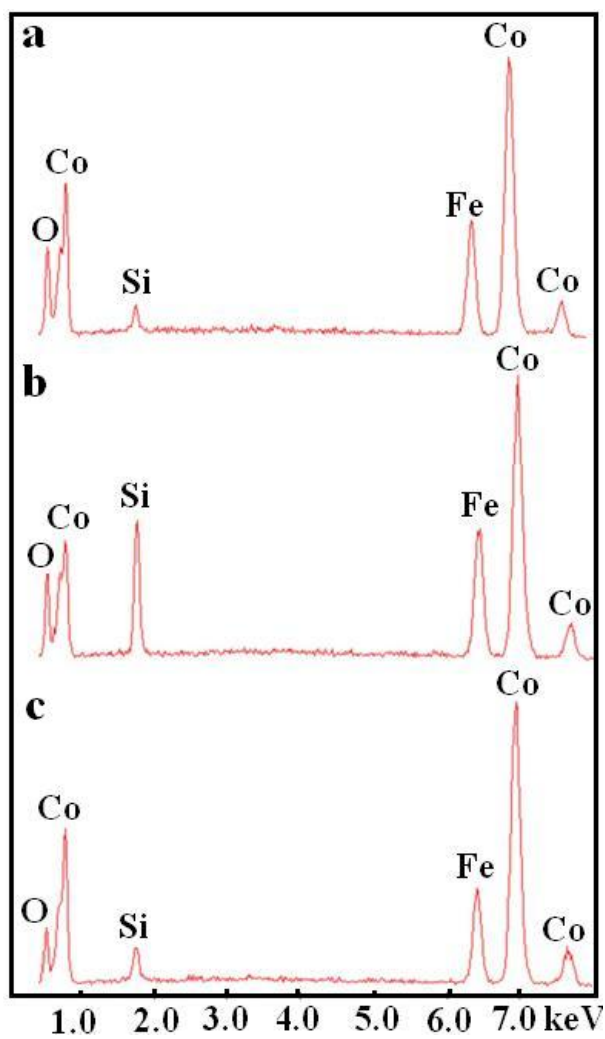


Figure S2 Energy dispersive X-ray spectroscopy (EDX) of Co/CoFe₂O₄ composites synthesized with different NaOH quantities: (a) 2 g, (b) 3 g, and (c) 4 g.

Details of Electrical Measurement.

The devices used in this investigation were fabricated by thermal evaporation in vacuum onto indium tin oxide (ITO) glass substrates with the sheet resistance of 25 Ω / sq. All the organics were evaporated with the rate of 0.05 nm/ s under high vacuum (5×10^{-5} Pa). LiF and Al were evaporated in another vacuum chamber (8.0×10^{-5} Pa) with the rates of 0.01 and 1 nm/s, respectively, without being exposed to the atmosphere. The thickness of these deposited layers and the evaporation rate of individual materials were monitored in vacuo with quartz crystal monitors.

The shape of the cathode was defined using a shadow mask during the deposition of Al. The active area of these devices as defined by the overlapping area of the cathode and the anode is 10 mm². After fabrication, all the devices were measured immediately in air at room temperature without encapsulation. Current density-voltage characteristics were measured by using a Keithley source measurement unit (Keithley 2400 and Keithley 2000) with a calibrated silicon photodiode.